Quantum kinetic description of Coulomb e ects in one-dimensional nano-transistors

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In this article, we combine the modi ed electrostatics of a one-dimensional transistor structure with a quantum kinetic formulation of C oulomb interaction and nonequilibrium transport. A multicon gurational self-consistent G reen's function approach is presented, accounting for uctuating electron numbers. On this basis we provide a theory for the simulation of electronic transport and quantum charging e ects in nano-transistors, such as gated carbon nanotube and whisker devices and one-dimensional CM O S transistors. Single-electron charging e ects arise naturally as a consequence of the C oulom b repulsion within the channel.

I. IN TRODUCTION

As scaling of eld-e ect-transistor (FET) devices reaches the deca-nanom eter regim e, multi-gate architectures and ultrathin active channel regions are mandatory in order to preserve electrostatic integrity. It has been shown that a coaxially gated nanow ire represents the ideal device structure for ultim ately scaled FETs.^{1,2} A variety of 1D nanostructures - such as carbon nanotubes, silicon nanowires or compound sem iconductor nano-whiskers - have been dem onstrated and intensive research has been devoted to the realization of eld-e ecttransistor action in these nanostructures.^{3,4,5,6} D ue to the sm all lateral extent in the nanom eter range, electronic transport through such nanowires is one-dimensional with only a few or even a single transverse mode participating in the current. As a result, increasingly less electrons are involved in the switching of a nanow ire transistor. In fact, even in devices with rather long channel lengths of 100nm, only on the order of 1-10 electrons constitute the charge in the channel for on-state voltage conditions. Hence, single-electron charging e ects are increasingly important and have to be taken into account.7,8,9

Two di erent approaches are commonly used to describe electronic transport in nano-transistors: A quantum kinetic approach based on real-time G reen's functions provides an excellent description of non-equilibrium states.^{10,11,12} Here, the C oulom b interaction is described in terms of a selfconsistent H artree potential, optionally combined with a spin-density-functional exchangecorrelation term in local density approximation (LDA – SDFT). However, this framework does not account for single-electron charging e ects without forcing integer electron numbers. A Itematively, the second approach considers a quasi-isolated nanosystem with a many-body form ulation of C oulom b interaction, including electronic transport on a basis of rate-equations.^{13,14,15,16,17,18,19} W hile predicting single-electron charging e ects correctly, the latter neglects dissipation and renorm alization e ects due to the source and drain contacts.

Here, we present a novel approach that allows to com bine a quantum kinetic description of non-equilibrium electron transport with non-local many-body Coulom b e ects in one-dim ensionalFET nanodevices.W ithin our approach, single-electron charging e ects arise naturally as a consequence of the Coulomb interaction. Our formalism contains two central ingredients: In order to cope with particle-number uctuations under nonequilibrium conditions, we introduce a multi-con gurational self-consistent G reen's function algorithm . Secondly, we consider a one-dim ensional C oulom b G reen's function for the transistor channel that allows to properly incorporate m any-body interaction e ects into a quantum kinetic approach with electrostatic boundary conditions for a realistic FET.As an example, we calculate the transfer characteristics of a nanow ire transistory ith Schottky-barriers (SB) at the contact-channel interfaces.

II. COULOM B GREEN'S FUNCTION

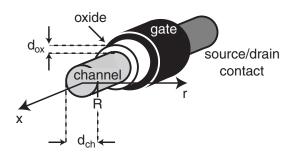


FIG.1: Schematic view of a 1D FET geometry. $(d_{ox} \text{ and } d_{ch})$ denote the gate insulator thickness and the channel diam eter of the nano-transistor, respectively.)

Consider a coaxially gated eld-e ect-transistor as illustrated in Fig.1. A cylindrical sem iconducting channel m aterial is surrounded by a thin dielectric and a m etallic gate electrode. The electrostatic potential V inside such a one-dimensional (1D) transistor channel obeys a m odi ed Poisson equation^{1,20}

$$\frac{\theta^2}{\theta x^2} V(x) - \frac{1}{2} V(x) = \frac{1}{0 \text{ ch} S} (x) - \frac{1}{2} V_G; \quad (1)$$

where is the 1D charge density. V_G denotes the gate potential and $S = d_{ch}^2 = 4$ is the electrice cross-sectional area. The characteristic length is related to the spatial separation of the gate electrode from the channel (which should be smaller than the total length L of the channel).^{1,20} N ote that Eq. (1) is an appropriate description for coaxial as well as planar transistor geom etries, di ering only in the characteristic length . In the following, we assume perfect metallic source and drain contacts at the boundaries, yielding xed-potential boundary conditions due to given chemical potentials within these contacts.

A key ingredient in our formalism is the usage of a C oulomb G reen's function for the description of charge interaction within the channel. This allows us to form ulate classical electrostatics (with boundary conditions) and m any-body interaction between electrons on equal footing. The corresponding C oulomb G reen's function of the gated channel (with 0 x;x⁰ L and vanishing potential at the boundaries 0;L) can readily be obtained as

$$v(\mathbf{x};\mathbf{x}^{0}) = \frac{1}{2} e^{\frac{j\mathbf{x} \cdot \mathbf{x}^{0}j}{2}} e^{\frac{\mathbf{x}+\mathbf{x}^{0}}{2}}$$
(2)
+
$$\frac{1}{2} e^{\frac{\mathbf{L}}{2}} e^{\frac{\mathbf{c} \cdot \mathbf{x}^{0}}{2}} \frac{\cosh \frac{\mathbf{x}+\mathbf{x}^{0}}{2}}{\sinh \frac{\mathbf{L}}{2}} \frac{\cosh \frac{\mathbf{x}+\mathbf{x}^{0}}{2}}{\sinh \frac{\mathbf{L}}{2}} \mathbf{A} :$$

(In contrast, if we considered open boundary conditions, we would obtain $v(x;x^0) = (=2) \exp(\frac{i}{x} x^0 = i)$ instead.) For a given charge density inside the channel, the potential thus reads

$$V(x) = \frac{1}{0 \text{ ch } S}^{Z} dx^{0} v(x;x^{0}) (x^{0}) + V_{\text{ext}}(x); \quad (3)$$

with the external potential contribution

$$V_{\text{ext}}(\mathbf{x}) = \frac{\sinh \frac{\mathbf{L} \cdot \mathbf{x}}{\sin h}}{\sinh \frac{\mathbf{L}}{2}} V_{\text{S}} + \frac{\sinh \frac{\mathbf{x}}{\sin h}}{\sinh \frac{\mathbf{L}}{2}} V_{\text{D}} \qquad (4)$$
$$+ \frac{1}{2} d\mathbf{x}^{0} \mathbf{v}(\mathbf{x};\mathbf{x}^{0}) V_{\text{G}};$$

where V_S and V_D denote the contact potentials.

III. SYSTEM HAM ILTONIAN

In this article, we make use of a tight-binding description of the system, represented by a localized 1D singleparticle basis f_j(x;)g (where the single-particle index j represents a combined orbital, site, and spin multiindex.) The total system H am iltonian H = H $_0$ + H $_{ee}$ + H $_S$ + H $_D$ can be split into four parts. H $_0$ contains all single-particle term s of the transistor channel:

$$H_{0} = \begin{array}{c} X \\ h_{jk} c_{j}^{v} c_{k}; \end{array}$$
(5)

$$h_{jk} = e dx_{j}(x;) k(x;) V_{dop}(x) + V_{ext}(x) + j_{k}d_{j} + t_{jk};$$

with the electron annihilation operator c_j for state j. The composition of the channel (material-speci c properties, layer sequence, etc.) is described by d_j and o -diagonal hopping matrix elements $t_{jk} \cdot ^{21,22} V_{dop}$ denotes the potential resulting from xed charges $_{dop}$ (due to ionized doping atom s), whereas V_{ext} stems from external charges due to the applied drain-source voltage and the gate in-uence (see Eq. (4)).

Furtherm ore, H_s and H_D are the H am iltonians for the source and drain contacts, respectively. Latter also contain the corresponding hopping terms to the outer ends of the channel region, providing electron injection and absorption. Each contact is assumed to be in a state of local equilibrium with an individual chem ical potential according to the applied voltage. (See also Eqs. (9), (12) below .)

M ost importantly, H $_{ee}$ describes the many-body C oulom b interaction between electrons within the channel region:¹⁹

$$H_{ee} = \frac{1}{2} \sum_{i;j;k;l}^{X} V_{m jkl} c_{m}^{Y} c_{j}^{Y} c_{k} c_{l};$$
(6)

with Coulomb matrix elements

$$V_{m jkl} = \frac{e^{2}}{\frac{1}{0} e^{3} ch^{2}} X Z Z dx dx^{0} v(x;x^{0})$$
(7)
$$\int_{m}^{m} (x;) \int_{j}^{m} (x^{0}; 0) k(x^{0}; 0) dx dx^{0} v(x;x^{0})$$
(7)

which employ the C oulom b G reen's function Eq. (2).

IV. QUANTUM KINETICS

A quantum kinetic description of the system (under nonequilibrium conditions in particular) is obtained via the usage of a real-time G reen's functions form alism $.^{23,24,25}$ The retarded and lesser (two-point) G reen's functions in the time dom ain are given by

$$G_{jk}^{r}(t) = i(t)h c_{j}(t); c_{k}^{y}(0) i;$$
(8)
$$G_{jk}^{<}(t) = ihc_{k}^{y}(0)c_{j}(t)i;$$

for steady-state conditions. In the following, we will consider the Equation transformed functions, de ned via G (E) = (1=h) dtexp (iE t=h)G (t).

For temperatures T well above the K ondo temperature of the system, the C oulomb interaction can be treated independently of the contact coupling, albeit selfconsistently. In matrix notation, the D yson equation for the channel thus can be written $as^{10,25,26}$

$$G^{r} = G^{r0} + G^{r0} \begin{bmatrix} r \\ ee \end{bmatrix} + r \\ S^{r} + r \\ D^{r} \end{bmatrix} G^{r};$$
(9)

$$G^{<} = i f_{0} A
+ i (f_{S} f_{0}) G^{r} \\ S^{r} \\ G^{a} \\ + i (f_{D} f_{0}) G^{r} \\ D^{r} \\ D^{a};$$

with s i(r_{s}^{r} a_{s}^{a}), p i(r_{D}^{r} a_{D}^{a}) and A i(G^r G^a). f_s and f_D are the local source and drain Ferm i distribution functions, respectively, assuming local equilibrium within these reservoirs. On the other hand, f₀ denotes the equilibrium distribution function of the isolated channel system (typically, f₀ = f_D). Furtherm ore, G^{r0} (E h + i)¹ (with ! 0+) and G^a = G^{ry}.

Once $G^{<}$ has been obtained selfconsistently from Eq.(9), observables like the electron density $_{e}$ and the current I_{e} (through an arbitrary layer at x_{0}) can be calculated via

with the single-particle density-matrix

$$_{jk} = \frac{1}{2} dE \frac{1}{i} G_{kj}^{<}(E):$$
 (11)

The elective contact selfenergies due to the coupling of the channel to the source and drain regions (c = S;D) can be obtained as^{10,26,27}

$$r_{cjk}(\mathbf{E}) = t_{cjp} G_{cpq}^{r0}(\mathbf{E}) t_{cqk};$$
(12)

with the isolated contact Green's function $G_{\rm c}^{\rm r0}$ and contact-channel hopping term s $t_{\rm c}$.

The evaluation of the Coulomb selfenergy r_{ee} requires a suitable approximation scheme due to the innite G men's function hierarchy (which is a consequence of the two-particle interaction). As a rst-order expansion (Hartree-Fock diagrams), four-point G men's functions can be factorized into linear combinations of products of two-point functions.^{23,26} U sing this approximation, the C oulomb selfenergy reads

$$r_{eem 1} = \bigvee_{j;k}^{X} (V_{m jk1} \quad V_{jm k1}) \hat{j}_{jk} :$$
 (13)

Note that $\stackrel{<}{_{ee}} = 0$, and $\stackrel{r}{_{ee}}$ is non-local, herm it ian and energy-independent (static) within the considered approximation scheme; compare also with Ref. 26. For convenience, the Hartree potential (rst V term in Eq. (13))

$$V_{\rm H}(\mathbf{x}) = \frac{1}{0 \, {\rm ch} \, \rm S} \int_{0}^{X} d\mathbf{x}^0 \, v(\mathbf{x}; \mathbf{x}^0) \, e(\mathbf{x}^0; \, {}^0) \qquad (14)$$

can be separated from the retarded C oulom b selfenergy (com pare Eq. (3)), where the electron charge density $_{e}$ is given by Eq. (10). Hence, the total electrostatic potential of the system reads $V = V_{dop} + V_{H} + V_{ext}$.

For integer-num ber electron lling conditions, Eq. (13) provides an excellent description of the system for application-relevant temperatures. However, under nonequilibrium conditions, one has to deal with non-integer average lling situations, which are beyond the scope of a rst-order (mean-eld) selfenergy in general. In the following section, we will therefore present a multi-con gurational approach which is able to cope with such particle-num ber uctuations.

V. MULTI-CONFIGURATIONAL SELF-CONSISTENT GREEN'S FUNCTION

A therm odynam ic state of the transistor channel with uctuating electron number can be considered as a weighted mixture of many-body states with integer lling (con gurations) of relevant single-particle states. For a given $G^{<}$, relevant single-particle states are de ned as eigenstates of ^ (Eq. (11)) that exhibit signi cant occupation uctuations and have a su ciently small dephasing (due to the contact-coupling). This projection to a relevant single-particle subspace of dimension N reduces the resulting Fock subspace dimension 2^{N} signi cantly, rendering this approach numerically feasible.

For each con guration, the Coulomb selfenergy approximation Eq. (13) becomes adequate. Then the Green's function can be written as a con guration-average:

$$G = W G [^{1}];$$
 (15)

where $^{\prime}$ denotes the single-particle density-matrix (derived from $^{\prime}$) for conguration with weight w.G [$^{\prime}$] is the corresponding G reen's function (retarded and lesser) which is obtained by using Eqs. (9), (13).

The weight vector w de nes a projected nonequilibrium many-body statistical operator in the relevant Fock basis. (Note that the con gurations de ned abovem ight not be exact eigenstates of the projected many-body Ham iltonian, containing Eq. (6) in particular. In the following, we restrict ourselves to the dom inant diagonal elements of the many-body Ham iltonian in the relevant Fock basis.) Consequentely, the resulting manybody lesser G reen's function reads

$$G_{MB}^{<} [w]_{jk} (t) = i^{N} w e^{\frac{i}{h}(E E)t}$$
(16)
;
h jc_{k}^{V} j i h jc_{j} j i;

where j i denotes a relevant Fock state with energy E. In principle, w must be chosen such that $(G_{MB}^{<} [w]; G^{<}) = m$ in for a given $G^{<}$ within the relevant subspace, where measures the cumulative difference of spectral weights of corresponding resonances.

However, for most applications it is su cient to consider a vector w that maximizes the entropy at an effective temperature T (T;V_G;V_D) under the (weaker) subsidiary condition that ${}^{M}_{M-B}$ [w] = ^ within the relevant subspace, where ${}^{M}_{M-B}$ [w] denotes the many-body result.^{19,28,29} (Under moderate bias conditions, it is justie d to assume T T.)

In turn, $G^{<}$ from Eq. (15) can be taken as a new $G^{<}$, serving as an input for the calculation scheme described above. This de ness a self-consistency procedure for G and w, which we refer to as the multi-con gurational self-consistent G reen's function algorithm (MCSCG). Such an approach resembles the multi-con gurational self-consistent eld (MCSCF) approximation.³⁰ However, MCSCG deals with grand-canonical nonequilibrium states and considers an incoherent superposition (m ixture) of di errent con gurations. O byiously, coherent superpositions of m any-body states of varying particle num bers would be subject to strong dephasing due to the C oulom b interaction and the resulting entanglem ent with the environm ent.

H aving solved the m any-body diagonalization problem of relevant states, it is straight-forward to employ this approach to calculate higher-order correlation functions (w ithin the relevant subspace). Note that the MCSCG can also be interpreted as a means to construct a nonstatic $_{ee}$ for Eq. (9).

VI. EXAMPLE:SB-FET

In the following illustrative example, we consider a one-band nanow ire-FET with Schottky-barrier in jectors, having one localized orbital (with two spin directions) per site. Therefore, only Coulomb matrix elements of the form V_{ijji} are remaining. Furtherm ore, we assume nearest-neighbor hopping with a real hopping parametert = $h^2 = (2m a^2)$. We have used the following device param eters: The nom inally undoped channel has a diameter of $d_{ch} = 4nm$ and a length of L = 20nm (im plem ented as 20 sites with a spacing of a = 1nm). The channelwith _{ch} = 15 is surrounded by a gate oxide with $d_{ox} = 10$ nm and $o_{ox} = 3:9$, yielding 3:7nm . W e assum e an e ective electron m ass of $m = 0.05 m_e$ (giving t = 0:77eV). The m etallic source and drain contacts have a Schottky-barrier height of SB = 0:5eV. For sim plicity, the corresponding contact selfenergy is assumed to be of i = 2 (within the band at the outer ends the form _c of the channel) with 76m eV.Note that this param eter has to be chosen to match the actualm etal contact used in an experiment. However, it is uncritical for the electronic spectrum and single-electron charging e ects. The system temperature is $T = 77K \cdot Up$ to N = 6 adaptively chosen relevant single-particle states were taken into account, depending on the applied voltages (with V_{S} 0).

Fig.2 visualizes the local density of states (LDOS) for low drain-source bias conditions and two di erent gate

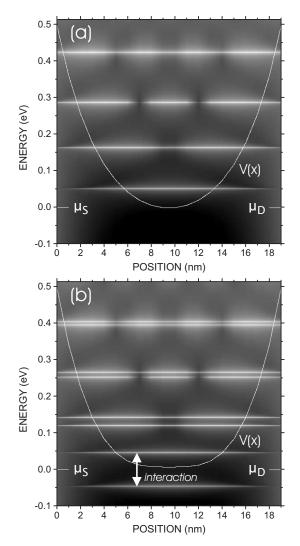


FIG. 2: Spectral function A (x;E) as a grayscale plot for (a) $V_{\rm G}$ = 0:59V and (b) $V_{\rm G}$ = 0:71V. In both cases, $V_{\rm D}$ = 2mV is chosen. The resulting average electron number within the channel is (a) N $_{\rm e}$ 0 and (b) N $_{\rm e}$ 1 (the electron is located in the lowest resonance). The solid white line represents the m ean-eld potentialV (x), whereas $_{\rm S}$ and $_{\rm D}$ denote the chemical potentials of the source and drain contact, respectively. T = 77K.

voltages $V_G = 0.59V$ and $V_G = 0.71V$, where the average electron number in the channel becomes N_{e} and N_e 1, respectively. The existence of quasi-bound states (i.e. spatially and energetically localized resonances in the spectral function A) yields discrete singleelectron energies with associated interaction energies due to r_{ee}^{r} . Comparing the situation for N_e = 1 with N_e = 0, the single-electron resonances are moved to higher energies with respect to the lowest energy state due to the Coulomb repulsion. Note that each electron is not subject to its own Hartree potential (see lowest resonance in Fig. 2(b)) because r_{ee}^{r} does not contain unphysical self-interaction energies, but includes exchange term s and correctly accounts for the electron spin. In the shown example, the next higher available state for a second electron (with opposite spin) is separated by the interaction energy V_{00} 93m eV (see arrow in Fig. 2(b)). In general, energy levels are splitted by exchange energy terms, which have a signi cant in uence on the energy spectrum.

As a natural consequence of h + $\frac{1}{ee}$ we therefore expect to observe the e ect of a step-like electron lling (under conditions close to equilibrium in particular), energetically determ ined by single-electron levels and repulsion energies. This behavior in fact can be seen in F ig. 3, where the electron lling characteristics is plotted for a varying gate voltage and xed drain-source bias $V_D = 2m V$. Furtherm ore, C culom b oscillations in the accompanying current through the channel can be identic ed.

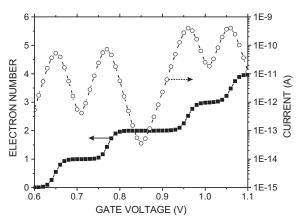
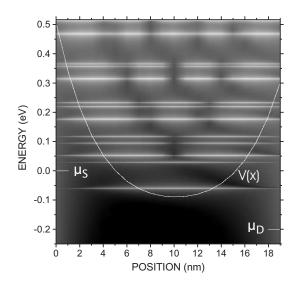
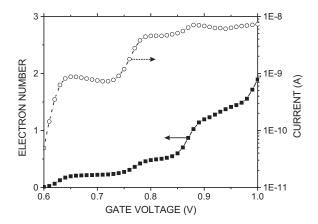


FIG.3: Single-electron tunneling characteristics for $V_D = 2m\,V$. The solid line with lled squares corresponds to the average electron number within the potential well, whereas the dashed line with open circles shows the drain current, exhibiting C oulom b oscillations. T = 77K.

Models solely based on a selfconsistent Hartree potential do not provide such quantization e ects due to Coulomb repulsion. With a Hartree approach (as used with conventional Schrodinger-Poisson solvers), spectral features are solely shifted in energy, depending on the average electron density. In contrast, the MCSCG (as well as the exact diagonalization of the isolated system) provides a superposition of fading spectra of integer electron num bers with full interaction energies, however, having spectral weights that depend on the average lling condition. The local density of states under nonequilibrium conditions as shown in Fig. 4 clearly demonstrates this behavior, where the average electron number within the well is N_e 0:22. In fact, the expectation value of the electron num ber need not be an integer, especially under non-equilibrium bias conditions, which can be seen in the corresponding transfer characteristics of the system as plotted in Fig. 5. Furtherm ore, Fig. 6 visualizes the output IV characteristics, where a nite drain voltage is required to pull the chem ical potential of the drain contact below the lowest energy level. These results clearly dem onstrate the strengths of the MCSCG approach, being able to describe single-electron charging e ects under



F~IG.4: Nonequilibrium spectral function A (x;E) as a grayscale plot for V_{G} = 0:7V and V_{D} = 0:2V. The resulting average electron number within the channel is N $_{e}$ 0:22. (The solid white line represents the mean-eld potential V (x), whereas $_{S}$ and $_{D}$ denote the chemical potentials of the source and drain contact, respectively.) T = 77K.



 $F\ IG$.5: Transfer characteristics for $V_D=0.2V$. The solid line with lled squares corresponds to the average electron number within the potential well, whereas the dashed line with open circles shows the drain current through the channel. T = 77K.

nonequilibrium bias conditions with uctuating electron numbers.

In general, we expect the m any-body C oulom b interaction to have a signi cant in pact on the electrical behavior of nano-transistors if the single-electron charging energy becomes 4kT, having consequences for the transconductance, onset/pinch-o voltages, sub-threshold currents, and system capacitance. A more detailed discussion of these aspects will be published elsew here.

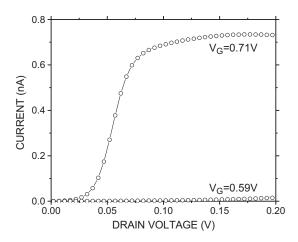


FIG .6: Output characteristics for V_G = 0:59V and V_G = 0:71V . T = 77K .

VII. CONCLUSION

The Coulomb G reen's function of a one-dimensional FET in combination with a quantum kinetic description

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- ¹ C.P.Auth and J.D.P lum m er, IEEE Electron D ev.Lett. 18,74 (1997).
- ² H.-S.P.W ong, IBM J.Res. & Dev. 46, 133 (2002).
- ³ A. Javey, J. Guo, M. Paulsson, Q. W ang, D. M ann, M. Lundstrom, and H. Dai, Phys. Rev. Lett. 92, 106804 (2004).
- ⁴ Y.M.Lin, J.Appenzeller, J.Knoch, and P.Avouris, condmat/0501690 (2005), accepted for publication in IEEE Trans. Nanotechnol.
- ⁵ M.C.M cAlpine, R.S.Fiedman, S.Jin, K.H.Lin, W.U. W ang, and C.M.Lieber, N ano Lett. 3, 1531 (2003).
- ⁶ C.Thelander, T.M artensson, M.T.B joerk, B.J.Ohlson, M.W.Larsson, L.R.W allenberg, and L.Sam uelson, Appl. Phys.Lett. 83, 2052 (2003).
- ⁷ N.Yoneya, E.W atanabe, K.T sukagoshi, and Y.A oyagi, Appl.Phys.Lett. 79, 1465 (2001).
- ⁸ M. Suzuki, K. Ishibashi, K. Toratani, D. Tsuya, and Y.Aoyagi, Appl. Phys. Lett. 81, 2273 (2002).
- ⁹ I. Am lani, R. Zhang, J. Tresek, and R. K. Tsui, J. Vac. Sci. Technol. B 21, 2848 (2003).
- ¹⁰ R.Lake, G.Klimeck, R.C.Bowen, and D.Jovanovic, J. Appl.Phys. 81, 7845 (1997).
- ¹¹ X.Yongqiang, S.D atta, and M.A.R atner, J.Chem .Phys. 281, 151 (2002).
- ¹² X.Yongqiang, S.D atta, and M.A.R atner, J.Com p.Phys. 115, 4292 (2001).
- ¹³ C.W.J.Beenakker, Phys.Rev.B 44, 1646 (1991).
- ¹⁴ D.V.Averin, A.N.Korotkov, and K.K.Likharev, Phys. Rev.B 44, 6199 (1991).
- 15 D . Jovanovic and J.P. Leburton, Phys. Rev. B 49, 7474

of electronic transport enables us to describe m any-body charging e ects within the transistor channel. We have presented a multi-con gurational self-consistent G reen's function algorithm, which is able to cope with uctuating electron numbers under nonequilibrium conditions. In the discussed example of a nano-FET with Schottky-barrier injectors, we have visualized how singleelectron charging e ects arise naturally as a consequence of the m any-body C oulom b repulsion between quasibound states. The usage of a G reen's function form ulation perm its the system atic extension to further C oulom b diagram s and the consistent inclusion of phonon scattering.

W ith the presented theoretical approach, we are able to describe electronic transport and quantum charging e ects in 1D nano-transistors such as gated carbon nanotubes, sem iconductor whiskers, and 1D CM OS transistors (in coaxial and multi-gate planar geom etry).

(1993).

- ¹⁶ D.Weimann,W.Hausler, and B.Kramer, Phys.Rev.Lett. 74,984 (1995).
- $^{\rm 17}$ Y .Tanaka and H .A kera, Phys.Rev.B 53, 3901 (1996).
- ¹⁸ D. P fannkuche and S.E. Ulloa, Phys. Rev. Lett. 74, 1194 (1995).
- ¹⁹ K.M. Indlekofer and H.Luth, Phys. Rev. B 62, 13016 (2000).
- ²⁰ F.G. Pikus and K.K. Likharev, Appl. Phys. Lett. 71, 3661 (1997).
- ²¹ P.Vogl, H.P.H jalm arson, and J.D.D ow, J.Phys.Chem. Solids 44, 365 (1983).
- ²² J.A.St vneng and P.Lipavsky, Phys. Rev. B 49, 16494 (1994).
- ²³ W . Schafer and M . W egener, Sem iconductor Optics and Transport Phenomena (Springer-Verlag, 2002).
- ²⁴ H.Haug and A.-P. Jauho, Quantum K inetics in Transport and Optics of Sem iconductors (Springer-Verlag, 1998).
- ²⁵ S. Datta, Electronic Transport in Mesoscopic Systems (Cambridge University Press, 1995).
- ²⁶ L.E.Henrickson, A.J.Glick, G.W.Bryant, and D.F. Barbe, Phys. Rev. B 50, 4482 (1994).
- ²⁷ K.M. Indlekofer, J. Lange, A. Forster, and H. Luth, Phys. Rev. B 53, 7392 (1996).
- ²⁸ K.M. Indlekofer, J.P.Bird, R.Akis, D.K.Ferry, and S.M.Goodnick, Appl.Phys.Lett. 81, 2861 (2002).
- ²⁹ K.M. Indlekofer, J.P.Bird, R.Akis, D.K.Ferry, and S.M. Goodnick, J.Phys.: Condens. Matter 15, 147 (2003).
- ³⁰ M.W. Schmidt and M.S.Gordon, Ann. Rev. Phys. Chem. 49, 233 (1998).